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CONFIRMATION NO. 9892

SERIAL NUMBER 10/026,560	FILING DATE 12/27/2001 RULE	CLASS 285 714	GROUP ART UNIT 2818 2133	ATTORNEY DOCKET NO. 108075-00072	
APPLICANTS Masayuki Takeshige, Kasugai, JAPAN; Sumitaka Hibino, Kasugai, JAPAN; Kenji Yamada, Kasugai, JAPAN; <i>cb</i>					
** CONTINUING DATA ***** <i>cb</i>					
** FOREIGN APPLICATIONS ***** JAPAN 2001-174101 06/08/2001 <i>cb</i>					
IF REQUIRED, FOREIGN FILING LICENSE GRANTED ** 01/28/2002					
Foreign Priority claimed <input checked="" type="checkbox"/> yes <input type="checkbox"/> no 35 USC 119 (a-d) conditions <input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> Met after met Allowance Verified and Acknowledged <i>cb</i> Examiner's Signature Initials		STATE OR COUNTRY JAPAN	SHEETS DRAWING 10	TOTAL CLAIMS 18	INDEPENDENT CLAIMS 3
ADDRESS ARENT FOX KINTNER PLOTKIN & KAHN, PLLC Suite 600 1050 Connecticut Avenue, N.W. Washington, DC 20036-5339					
TITLE Test method and test system for semiconductor device					
FILING FEE RECEIVED 740	FEES: Authority has been given in Paper No. _____ to charge/credit DEPOSIT ACCOUNT No. _____ for following:		<input type="checkbox"/> All Fees <input type="checkbox"/> 1.16 Fees (Filing) <input type="checkbox"/> 1.17 Fees (Processing Ext. of time) <input type="checkbox"/> 1.18 Fees (Issue) <input type="checkbox"/> Other _____ <input type="checkbox"/> Credit		